

# Supporting Information for: “Optical characterization of ALD coated nanoporous alumina structures: Effect of sample geometry or coated layer material”

Ana Laura Cuevas <sup>1</sup>, Victor Vega <sup>2</sup>, Antonia Dominguez <sup>1</sup>, Ana Silvia González <sup>3,\*</sup>, Víctor M. Prida <sup>3,\*</sup> and Juana Benavente <sup>4,\*</sup>

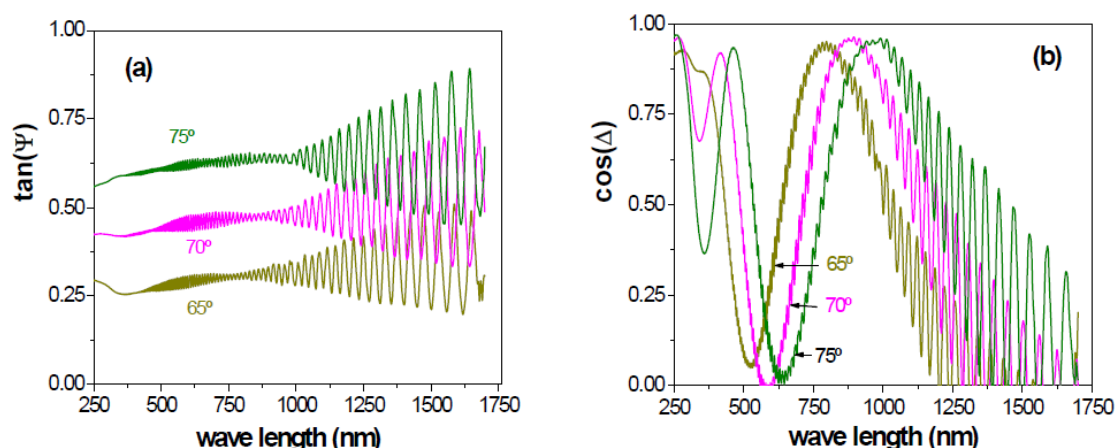
<sup>1</sup> Unidad de Nanotecnología, SCBI Centro, Universidad de Málaga, E-29071 Málaga, Spain

<sup>2</sup> Laboratorio de Membranas Nanoporosas, Servicios Científico-Técnicos, Universidad de Oviedo, E-33006 Oviedo, Spain

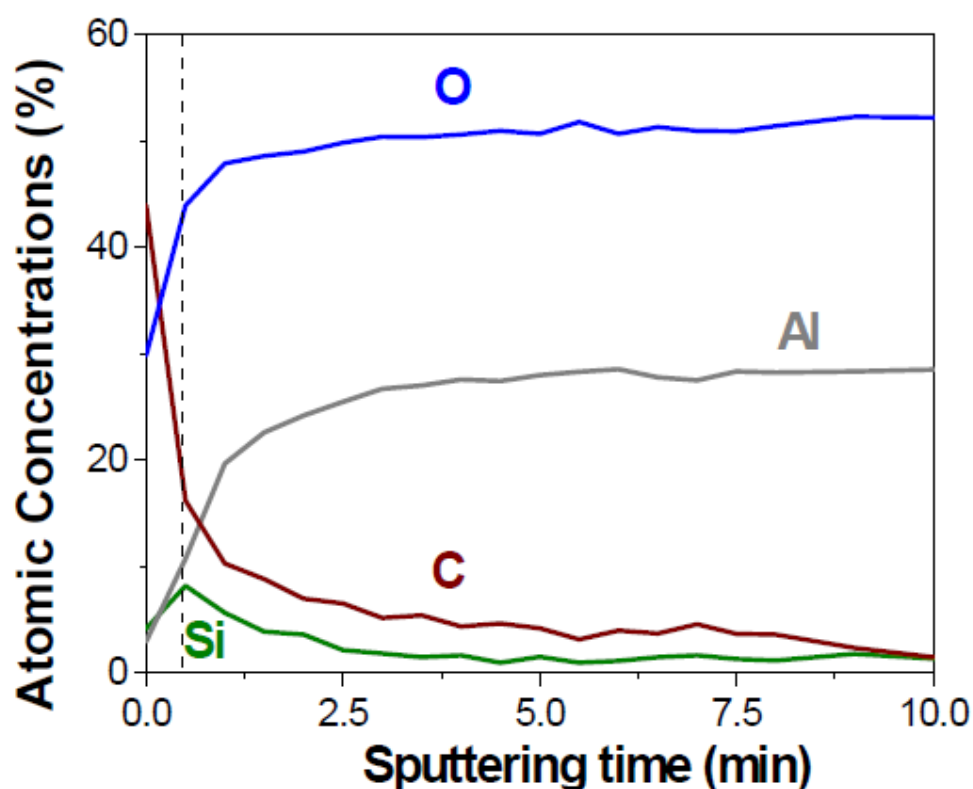
<sup>3</sup> Departamento de Física, Facultad de Ciencias, Universidad de Oviedo, E-33007 Oviedo, Spain

<sup>4</sup> Departamento de Física Aplicada I, Facultad de Ciencias, Universidad de Málaga, E-29071 Málaga, Spain

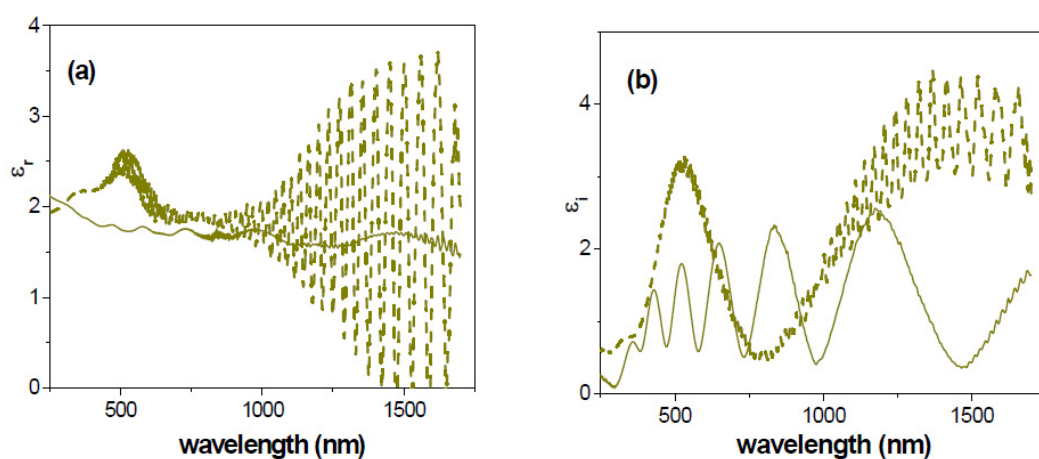
\* Correspondence :V.M.P.: vmpp@uniovi.es; J.B.: j\_benavente@uma.es



**Figure S1:** Wavelength dependence for  $\tan(\Psi)$  and  $\cos(\Delta)$  at three light incident angles: 65° (dark yellow lines), 70° (magenta lines) and 75° (green lines) for sample Ox(B)/SiO<sub>2</sub>. Without applying data refinement (smoothing)



**Figure S2:** Variation of atomic concentration percentages of the different elements detected on the Ox/SiO<sub>2</sub> sample surface with the XPS sputtering time.



**Figure S3:** Wavelength dependence of the dielectric constant (real part (a) and imaginary part (b)) for Ox(A)/SiO<sub>2</sub> sample (solid line) and Ox(B)/SiO<sub>2</sub> sample (dashed line) determined for a light incident angle of 65°.